Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/705,386	LIU ET AL.		
Examiner	Art Unit		
Thien F. Tran	2811		

SEARCHED						
Class	Subclass	Date	Examiner			
257	690, 713 734, 737 738, 778	2/9/2006	тт			
257	782-784	2/9/2006	П			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

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DATE	EXMR
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